

●General Description

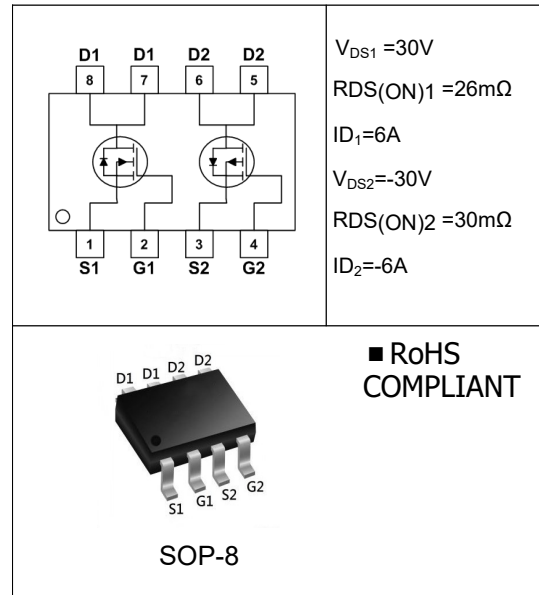
The N-ch and P-ch MOSFET LH26N30P uses trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. This device is suitable for high current load applications.

●Features

- Advance high cell density trench technology
- Low $R_{DS(on)}$ to minimize conductive loss
- Low Gate Charge for fast switching

●Application

- Lighting
- Power Supplies
- Wireless Charger



●Ordering Information:

Part Number	LH26N30P
Package	SOP-8
Basic Ordering Unit (pcs)	4000
Normal Package Material Ordering Code	LH26N30PS-SOP8-TAP
Halogen Free Ordering Code	LH26N30PS-SOP8-TAP-HF

●Absolute Maximum Ratings (TC = 25°C)

PARAMETER	SYMBOL	Value		UNIT
		N-Channel	P-Channel	
Drain-Source Breakdown Voltage	BV_{DSS}	30	-30	V
Gate-Source Voltage	V_{GS}	± 20	± 20	V
Continuous Drain Current, $T_C = 25^\circ C$	I_D	6	-6	A
Pulsed drain current ($T_C = 25^\circ C$, tp limited by T_{jmax}) ¹	I_{DM}	21	-12	A
Power Dissipation ²	$P_D(T_A = 25^\circ C)$	1.3	2.5	W
	$P_D(T_A = 70^\circ C)$	0.8	1.6	
Operating Temperature	T_J	-55~+150	-55~+150	°C
Storage Temperature	T_{STG}	-55~+150	-55~+150	°C

●Electronic Characteristics ($T_J=25$ Unless Otherwise Specified) **(N-Ch.)**

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=-50\mu A$	30	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS}=V_{DS}, I_D=250\mu A$	1.0	--	3.0	V
Drain-source On Resistance ¹	$R_{DS(ON)}$	$V_{GS}=10V, I_D=6.7A$	--	26	34	mΩ
		$V_{GS}=4.5V, I_D=5.0A$	--	35	40	
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=30V, V_{GS}=0V, T_J=25^\circ C$	--	--	1	μA
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 16V, V_{DS}=0V$	--	--	±10	μA
Forward Transconductance	G_{FS}	$V_{DS}=5V, I_D=5A$	--	12	--	S
Input Capacitance	C_{iss}	$V_{GS}=0V,$ $V_{DS}=15V,$ $f=1.0MHz$	--	380	--	pF
Output Capacitance	C_{oss}		--	64	--	
Reverse transfer Capacitance	C_{rss}		--	41	--	
Turn-On Delay Time	$T_{d(on)}$	$V_{DD}=15V,$ $V_{GS}=10V,$ $R_G=6\Omega,$ $I_D=1A$	--	8.8	--	nS
Turn-Off Delay Time	$T_{d(off)}$		--	31.8	--	
Turn-On Rise Time	T_r		--	9.6	--	
Turn-Off Fall Time	T_f		--	3.9	--	
Total Gate Charge	Q_g	$I_D=5A,$ $V_{DS}=15V,$ $V_{GS}=4.5V$	--	5.8	---	nC
Gate-to-Source Charge	Q_{gs}		--	2.9	--	
Gate-to-Drain Charge	Q_{gd}		--	2.1	---	
Continuous Diode Forward Current ¹	I_S	$V_{GS}=V_{DS}=0V,$ Force Current	--	--	6	A
Pulsed Diode Forward Current	I_{SM}	--	--	--	21	A
Diode Forward Voltage	V_{SD}	$T_J=25^\circ C, I_S=-1A,$ $V_{GS}=0V$	--	0.8	1.2	V

●Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case	R_{thJC}	22	°C/W
Thermal Resistance Junction-ambient($\leq 10s$) ³	R_{thJA}	90	°C/W

Notes:

1. Pulse Test : Pulse width $\leq 300 \mu s$, Duty cycle $\leq 2\%$;

2. The Power Dissipation is limited by $150^\circ C$ junction temperature;

3. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.

●Electronic Characteristics(T_j=25 Unless Otherwise Specified)**(P-Ch.)**

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250uA	-30	--	--	V
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} =V _{DS} , I _D =-250uA	-1.0	--	-3.0	V
Drain-source On Resistance ¹	R _{DS(ON)}	V _{GS} =-10V, I _D =-5.3A	--	25	30	mΩ
		V _{GS} =-4.5V, I _D =-4.2A	--	32	40	
Drain-Source Leakage Current	I _{DSS}	V _{DS} =-24V, V _{GS} =0V, T _J =25℃	--	--	-1	uA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =±20, V _{DS} =0V	--	--	±100	nA
Forward Transconductance	G _{FS}	V _{DS} =-5V, I _D =-5A	--	17	--	S
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = -15V, f = 1.0MHz	--	840	--	pF
Output Capacitance	C _{oss}		--	120	--	
Reverse transfer Capacitance	C _{rss}		--	35	--	
Turn-On Delay Time	T _{d(on)}	V _{DD} =-15V, V _{GS} =-10V, R _G =3.3Ω, I _D =-61A	--	32	--	nS
Turn-Off Delay Time	T _{d(off)}		--	58	--	
Turn-On Rise Time	T _r		--	13	--	
Turn-Off Fall Time	T _f		--	6	--	
Total Gate Charge	Q _g	I _D =-5.3A, V _{DS} = -15V, V _{GS} =-4.5V	--	20.6	---	nC
Gate-to-Source Charge	Q _{gs}		--	6	--	
Gate-to-Drain Charge	Q _{gd}		--	5.5	---	
Continuous Diode Forward Current ¹	I _S	V _{GS} =V _{DS} =0V, Force Current	--	--	-6	A
Pulsed Diode Forward Current	I _{SM}	--	--	--	-12	A
Diode Forward Voltage	V _{SD}	T _j =25℃, I _S =-1A, V _{GS} =0V	--	--	-1.2	V
Reverse Recovery Time	t _{rr}	I _f =I _S di _f /dt=100A/μs	--	15	--	ns
Reverse Recovery Charge	Q _{rr}		--	10	--	uC

●Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case	R _{thJC}	24	℃/W
Thermal Resistance Junction-ambient(t≤10s) ³	R _{thJA}	45	℃/W

Notes:

1.Pulse Test : Pulse width ≤ 300 μs, Duty cycle ≤ 2% ;

2.The Power Dissipation is limited by 150℃ junction temperature;

3.Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.

• **Typical Characteristics(N-Ch.)**

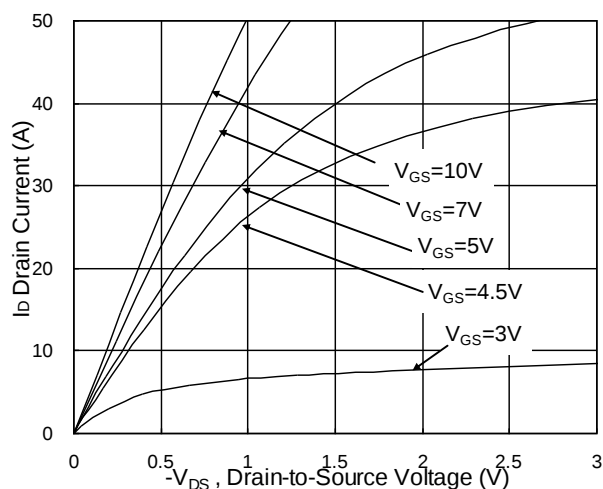


Fig.1 Typical Output Characteristics

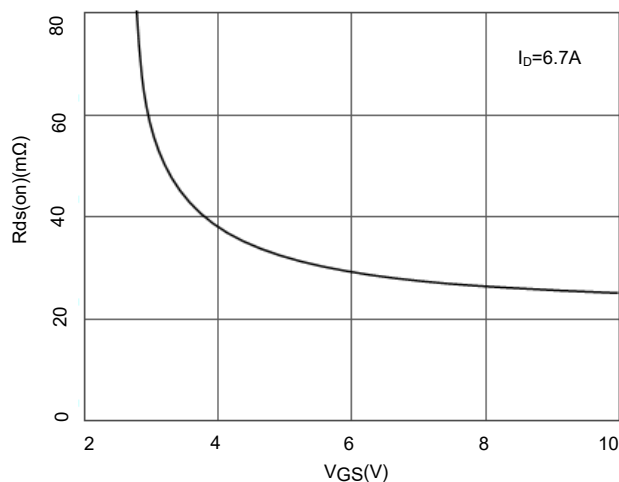


Fig.2 On-Resistance v.s Gate-Source

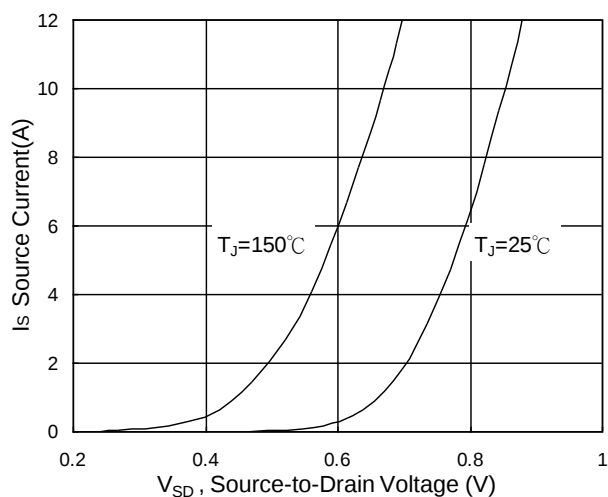


Fig.3 Forward Characteristics of Reverse

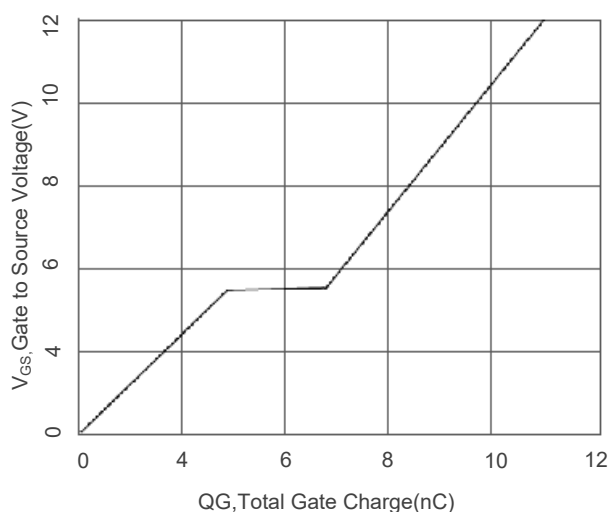


Fig.4 Gate-Charge Characteristics

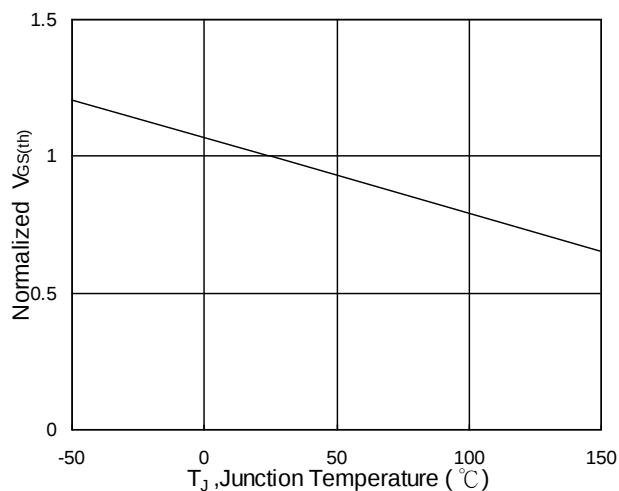


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

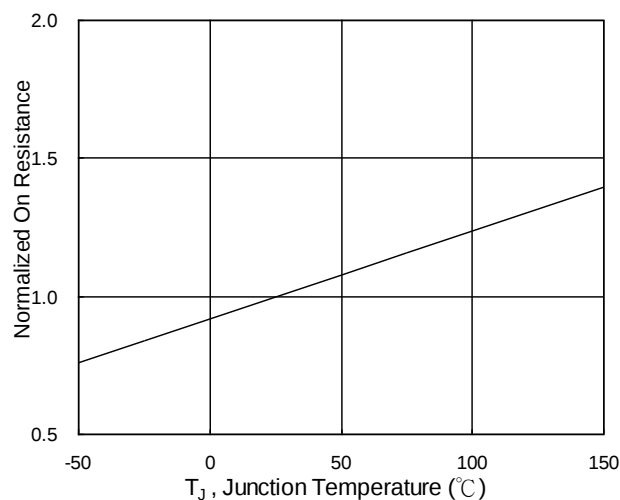


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

• Typical Characteristics(N-Ch.)(Cont.)

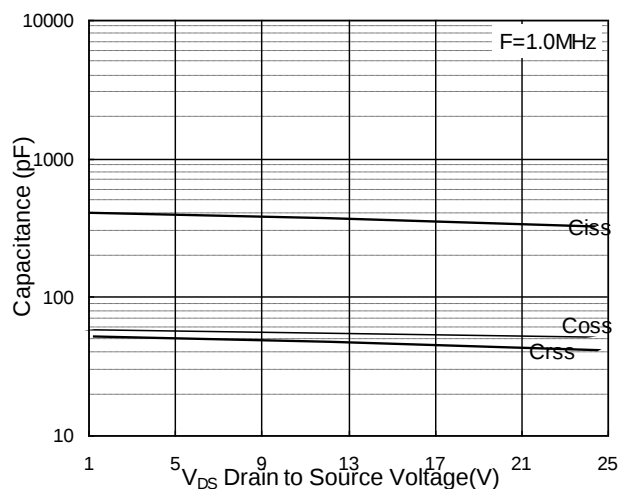


Fig.7 Capacitance

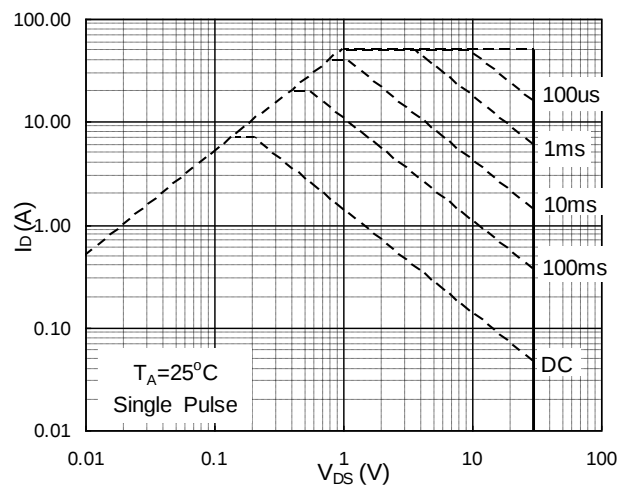


Fig.8 Safe Operating Area

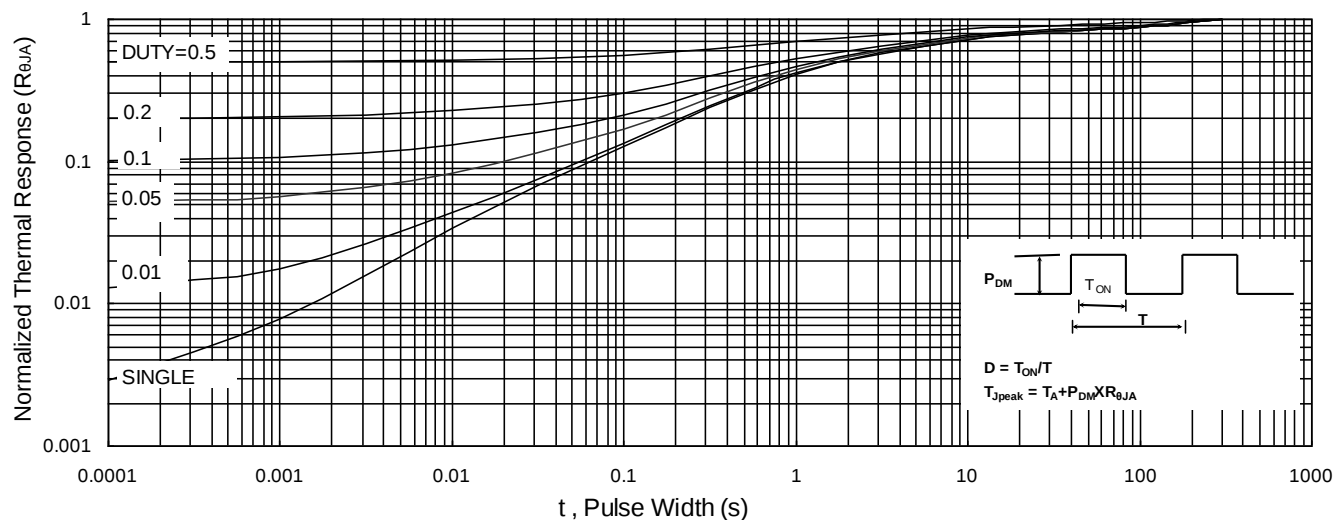


Fig.9 Normalized Maximum Transient Thermal Impedance

• Test Circuits & Waveforms

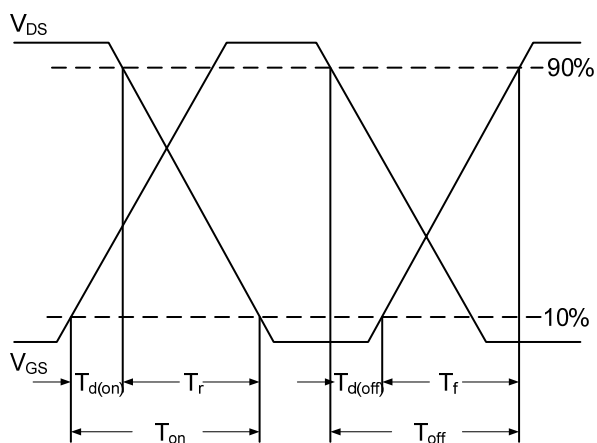


Fig.10 Switching Time Waveform

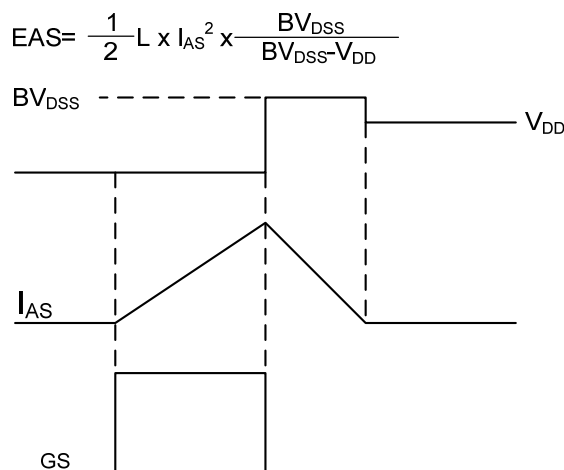


Fig.11 Unclamped Inductive Waveform

•**Typical Characteristics(P-Ch.)**

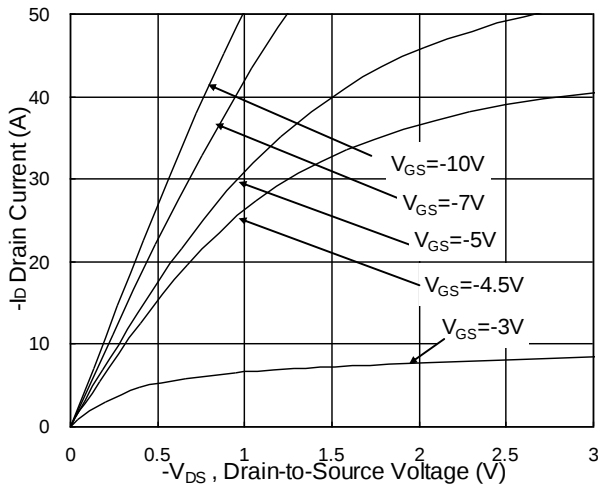


Fig.1 Typical Output Characteristics

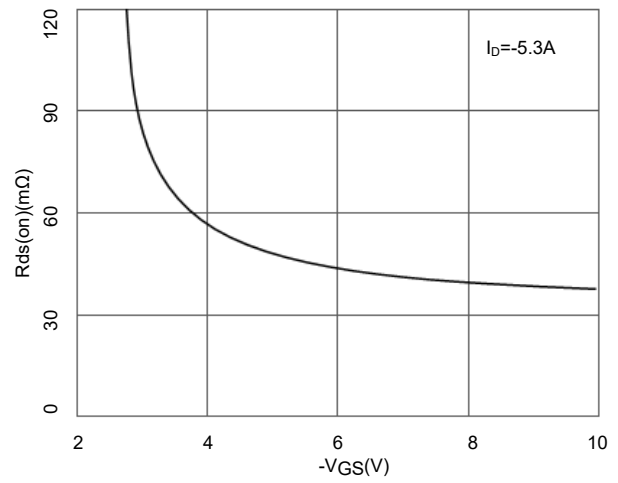


Fig.2 On-Resistance v.s Gate-Source

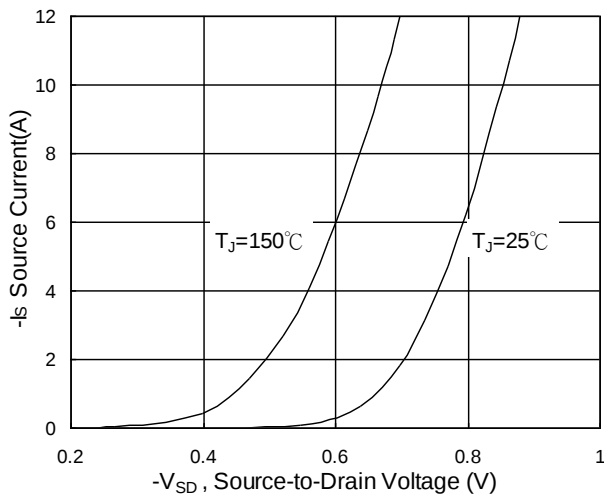


Fig.3 Forward Characteristics of Reverse

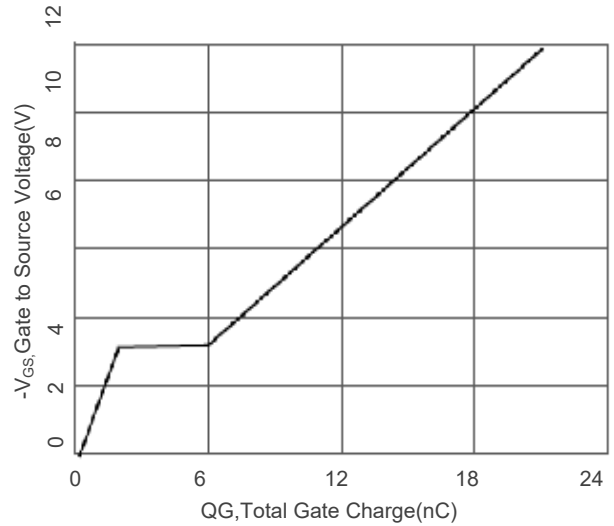


Fig.4 Gate-Charge Characteristics

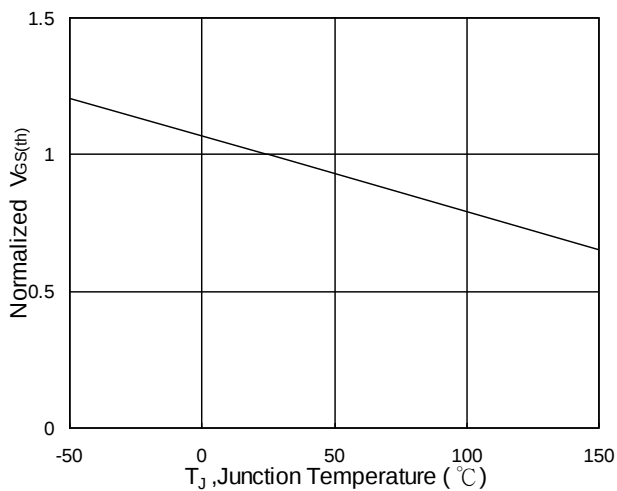


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

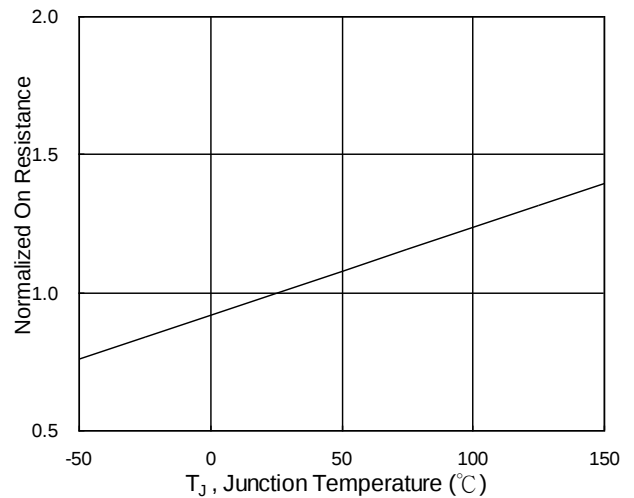


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

• **Typical Characteristics(P-Ch.)**(Cont.)

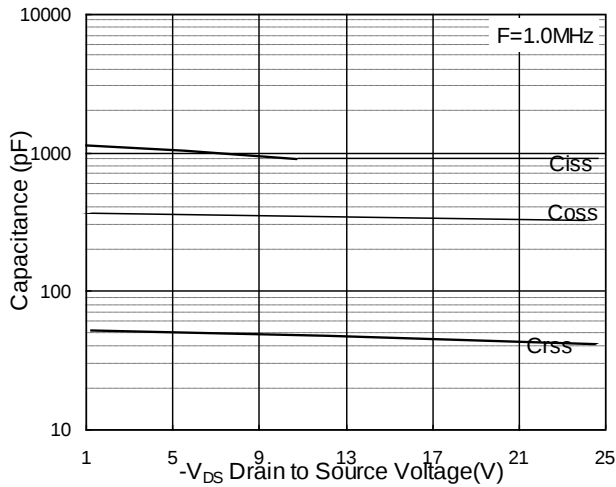


Fig.7 Capacitance

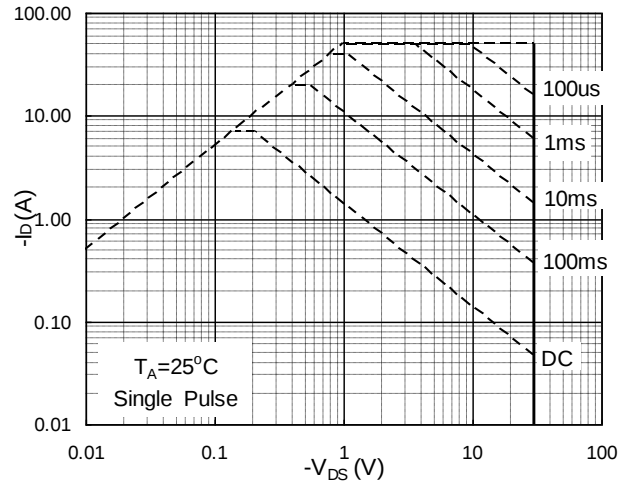


Fig.8 Safe Operating Area

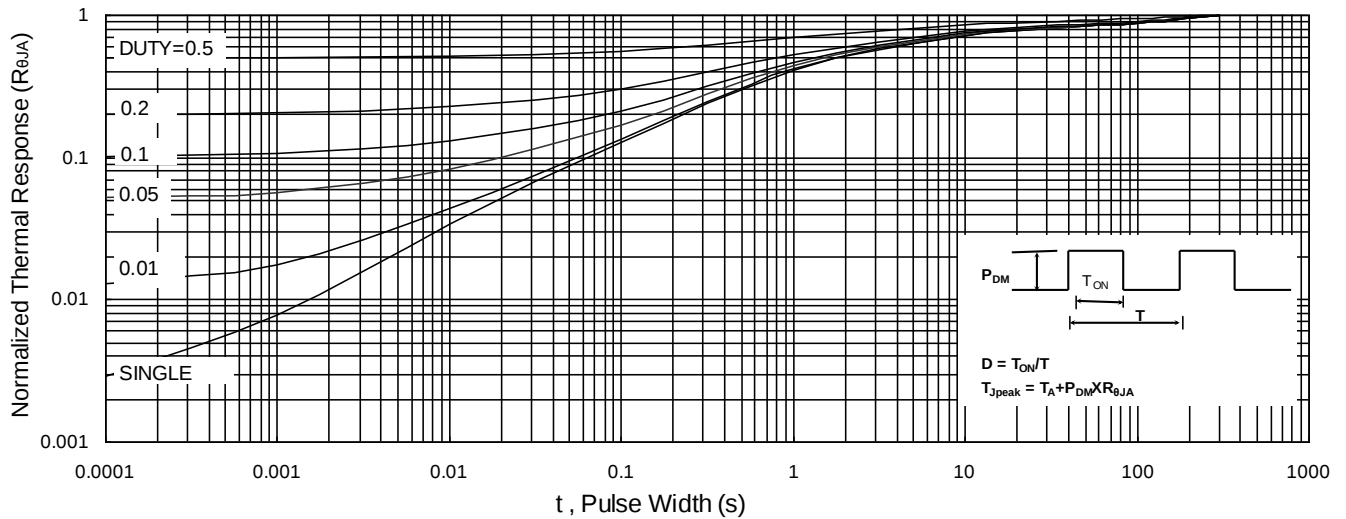


Fig.9 Normalized Maximum Transient Thermal Impedance

• **Test Circuits & Waveforms**

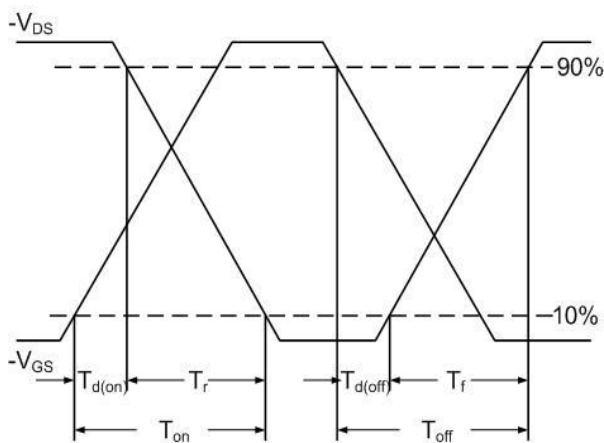


Fig.10 Switching Time Waveform

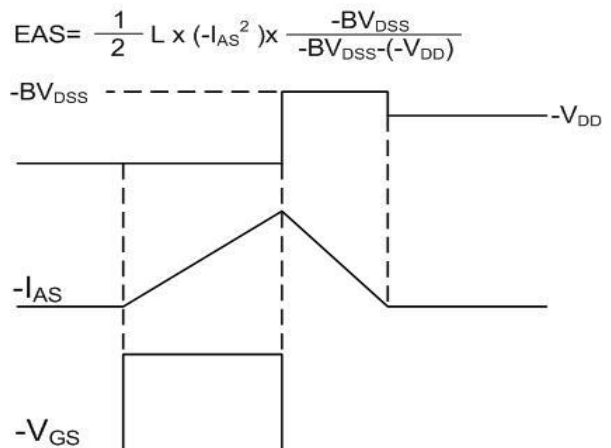


Fig.11 Unclamped Inductive Switching Waveform

●Dimensions (SOP-8)

UNIT:mm

SYMBOL	min	max	SYMBOL	min	max
A	1.30	1.60	e	1.27BSC	
A1	1.35	1.85	L	0.40	1.30
b	0.30	0.60			
C	0.15	0.35			
D	4.60	5.20			
E	3.70	4.10			
E1	5.70	6.30			

